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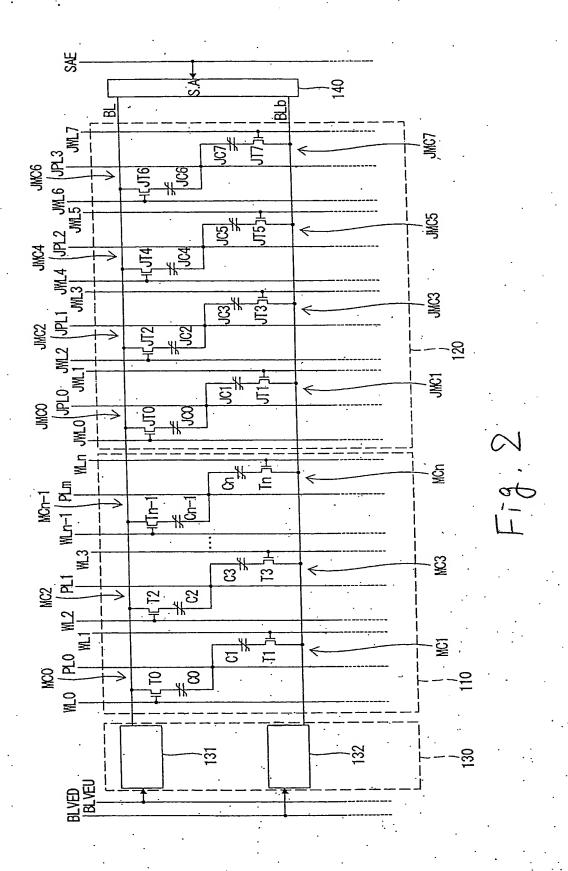
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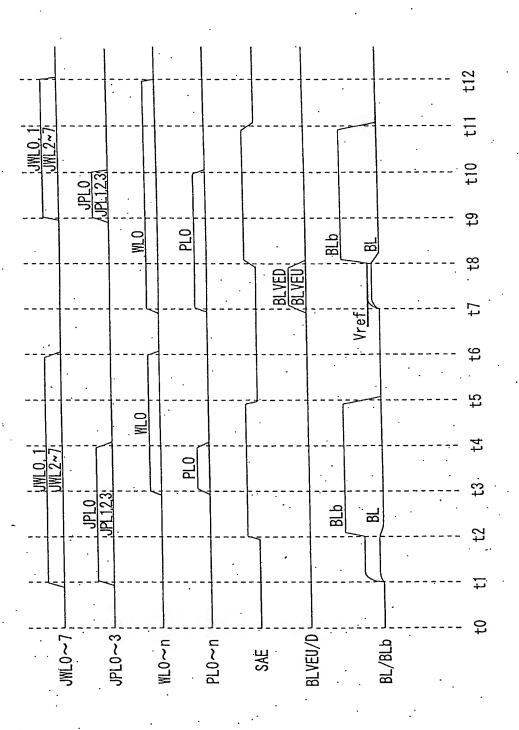
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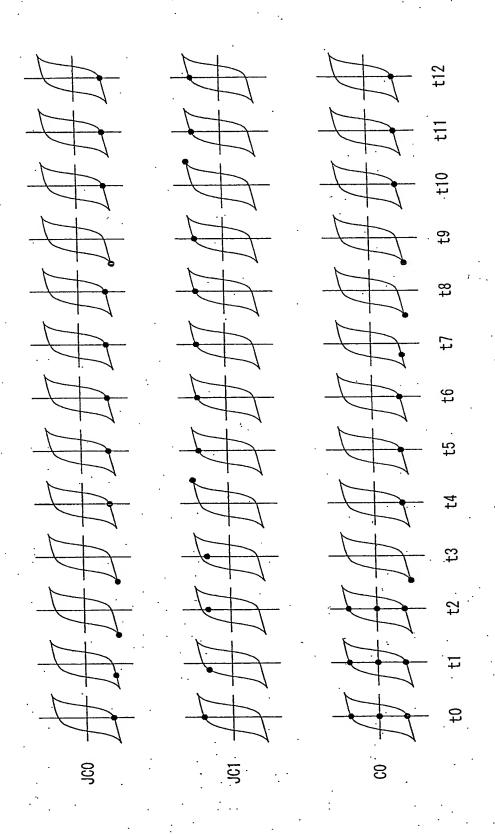
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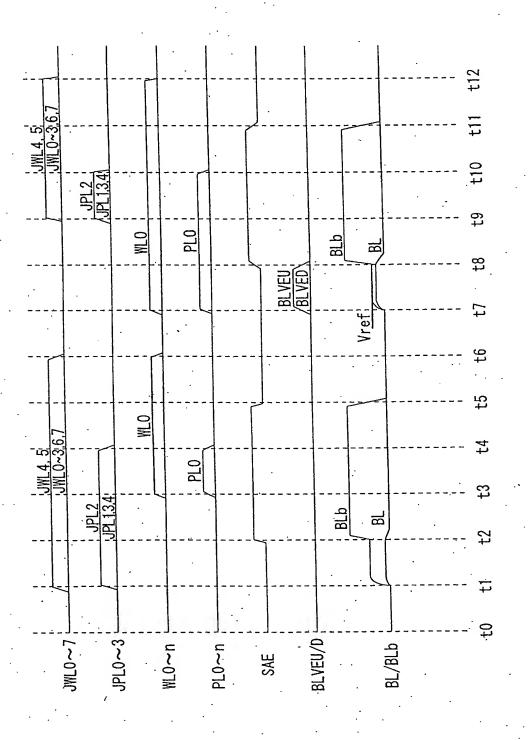




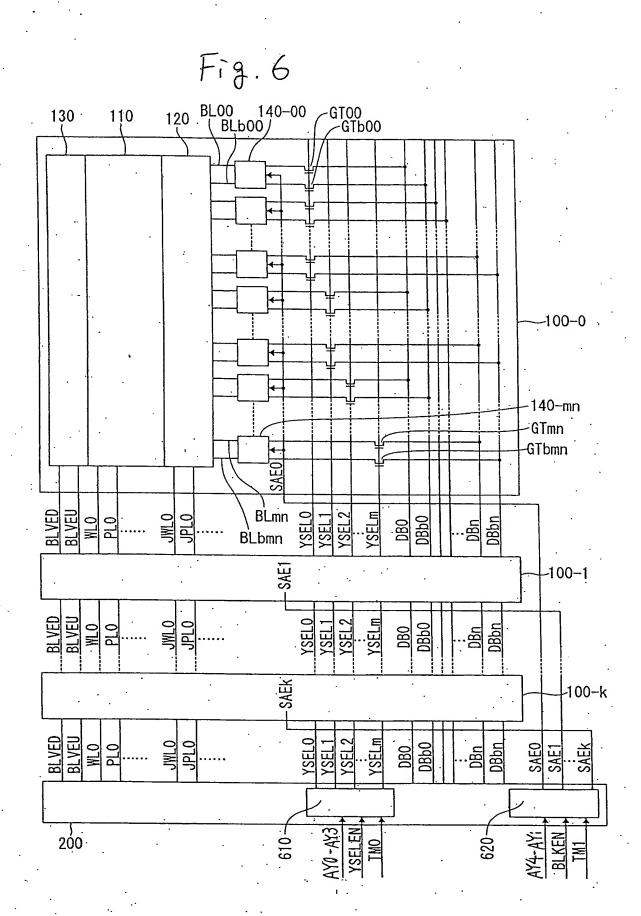
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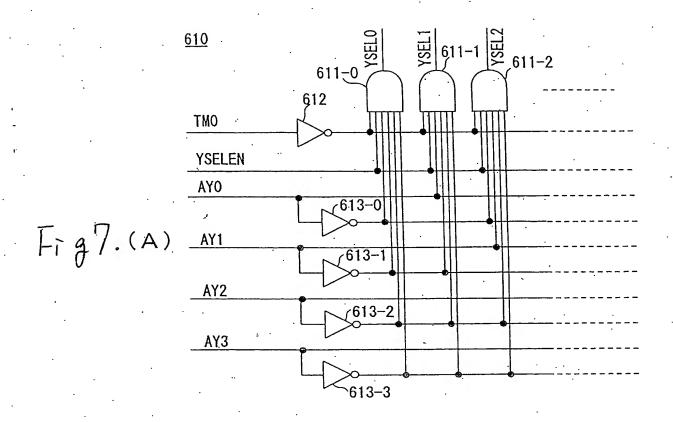


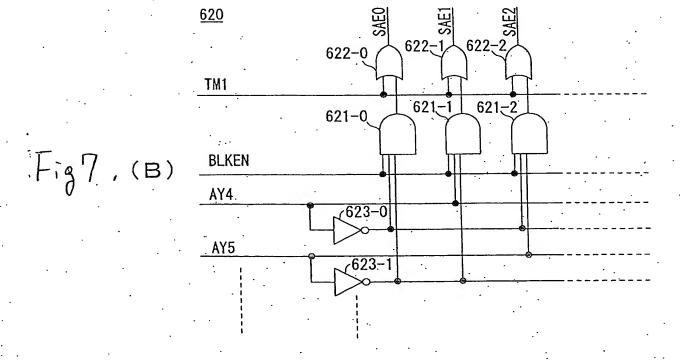
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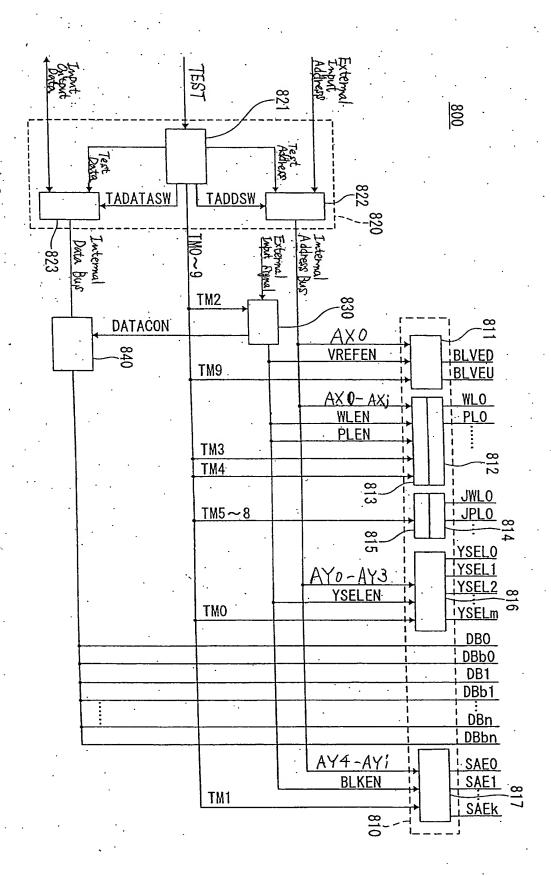


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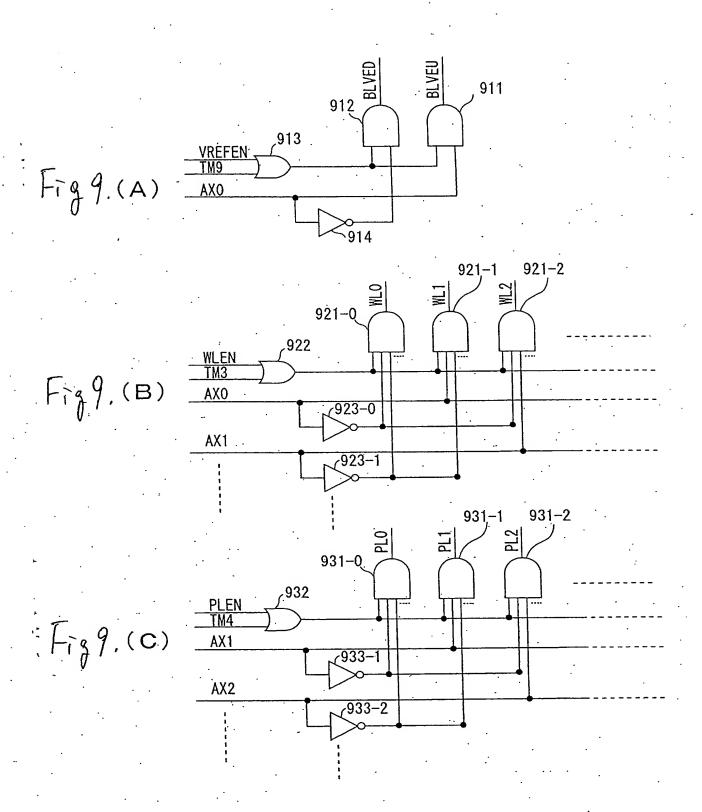








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## FERROELECTRIC MEMORY DEVICE HAVING TEST MEMORY CELL Application No. [New] – Attorney Doc. No. OKI.638 Inventor: Kazuhiko TAKAHASHI



